Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination
10/603,520	CHRISTIAN ET AL.
Examiner	Art Unit
Chau Nguyen	2176

SEARCHED			
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715	501.1	12/6/2005	CN
715	513	12/6/2005	CN
715	536	12/6/2005	CN
715	540	12/6/2005	CN
709	200	12/6/2005	CN
709	217	12/6/2005	CN
707	104.1	12/06/2005	CN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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	DATE	EXMR
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NPL Search on IEEE Database	12/8/2005	CN
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